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Application/Control No.	Applicant(s)/Patent under Reexamination
10/820,845	LEE, KWAN-HEE
Examiner	Art Unit

2879

Anne M. Hines

SEARCHED			
Class	Subclass	Date	Examiner
313	506	8/2/2006	Amil

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
searched East; see search history	8/2/2006	Amil	